



RADIO TEST REPORT

Test Report No. : 13382555S-A-R1

Applicant : FUJIFILM Corporation
Type of EUT : Reader/Writer
Model Number of EUT : ICT-3404U-A
FCC ID : W2Z-04000001
Test regulation : FCC Part 15 Subpart C: 2020
Test Result : Complied (Refer to SECTION 3.2)

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2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the limits of the above regulation.
4. The test results in this test report are traceable to the national or international standards.
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It does not cover administrative issues such as Manual or non-Radio test related Requirements. (if applicable)
7. The all test items in this test report are conducted by UL Japan, Inc. Shonan EMC Lab.
8. The opinions and the interpretations to the result of the description in this report are outside scopes where UL Japan has been accredited.
9. The information provided from the customer for this report is identified in SECTION 1.
10. This report is a revised version of 13382555S-A. 13382555S-A is replaced with this report.

Date of test: July 1 to 10, 2020

Representative test engineer: T. Kawakami
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Approved by: H. Shirasawa
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Engineer
Consumer Technology Division



CERTIFICATE 1266.03

- The testing in which "Non-accreditation" is displayed is outside the accreditation scopes in UL Japan.
 There is no testing item of "Non-accreditation".

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REVISION HISTORY

Original Test Report No.: 13382555S-A

Revision	Test report No.	Date	Page revised	Contents
- (Original)	13382555S-A	July 31, 2020	-	-
1	13382555S-A-R1	August 6, 2020	9	Correction of List of cables used: No.1 USB cable Length: 1.5 → 1.0 Shield-Cable: Unshielded → Shielded Shield-Connector: Unshielded → Shielded
			23	Addition of comment: “Since the transmitter signal is CW-like it is impractical to use a RBW setting of 1 – 5% of the emission bandwidth since the emission bandwidth will be proportional to the RBW.”

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Reference: Abbreviations (Including words undescribed in this report)

A2LA	The American Association for Laboratory Accreditation	MCS	Modulation and Coding Scheme
AC	Alternating Current	MRA	Mutual Recognition Arrangement
AFH	Adaptive Frequency Hopping	N/A	Not Applicable
AM	Amplitude Modulation	NIST	National Institute of Standards and Technology
Amp, AMP	Amplifier	NS	No signal detect.
ANSI	American National Standards Institute	NSA	Normalized Site Attenuation
Ant, ANT	Antenna	NVLAP	National Voluntary Laboratory Accreditation Program
AP	Access Point	OBW	Occupied Band Width
ASK	Amplitude Shift Keying	OFDM	Orthogonal Frequency Division Multiplexing
Atten., ATT	Attenuator	P/M	Power meter
AV	Average	PCB	Printed Circuit Board
BPSK	Binary Phase-Shift Keying	PER	Packet Error Rate
BR	Bluetooth Basic Rate	PHY	Physical Layer
BT	Bluetooth	PK	Peak
BT LE	Bluetooth Low Energy	PN	Pseudo random Noise
BW	BandWidth	PRBS	Pseudo-Random Bit Sequence
Cal Int	Calibration Interval	PSD	Power Spectral Density
CCK	Complementary Code Keying	QAM	Quadrature Amplitude Modulation
Ch., CH	Channel	QP	Quasi-Peak
CISPR	Comite International Special des Perturbations Radioelectriques	QPSK	Quadri-Phase Shift Keying
CW	Continuous Wave	RBW	Resolution Band Width
DBPSK	Differential BPSK	RDS	Radio Data System
DC	Direct Current	RE	Radio Equipment
D-factor	Distance factor	RF	Radio Frequency
DFS	Dynamic Frequency Selection	RMS	Root Mean Square
DQPSK	Differential QPSK	RSS	Radio Standards Specifications
DSSS	Direct Sequence Spread Spectrum	Rx	Receiving
EDR	Enhanced Data Rate	SA, S/A	Spectrum Analyzer
EIRP, e.i.r.p.	Equivalent Isotropically Radiated Power	SG	Signal Generator
EMC	ElectroMagnetic Compatibility	SVSWR	Site-Voltage Standing Wave Ratio
EMI	ElectroMagnetic Interference	TR	Test Receiver
EN	European Norm	Tx	Transmitting
ERP, e.r.p.	Effective Radiated Power	VBW	Video BandWidth
EU	European Union	Vert.	Vertical
EUT	Equipment Under Test	WLAN	Wireless LAN
Fac.	Factor		
FCC	Federal Communications Commission		
FHSS	Frequency Hopping Spread Spectrum		
FM	Frequency Modulation		
Freq.	Frequency		
FSK	Frequency Shift Keying		
GFSK	Gaussian Frequency-Shift Keying		
GNSS	Global Navigation Satellite System		
GPS	Global Positioning System		
Hori.	Horizontal		
ICES	Interference-Causing Equipment Standard		
IEC	International Electrotechnical Commission		
IEEE	Institute of Electrical and Electronics Engineers		
IF	Intermediate Frequency		
ILAC	International Laboratory Accreditation Conference		
ISED	Innovation, Science and Economic Development Canada		
ISO	International Organization for Standardization		
JAB	Japan Accreditation Board		
LAN	Local Area Network		
LIMS	Laboratory Information Management System		

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SECTION 1: Customer information

Company Name : FUJIFILM Corporation
Address : 7-3, Akasaka 9-chome, Minato-ku, Tokyo 107-0052, Japan
Telephone Number : +81-3-6271-1654
Facsimile Number : +81-3-6271-1189
Contact Person : Takao Ozaki

The information provided from the customer is as follows;

- Applicant, Type of EUT, Model Number of EUT, FCC ID on the cover and other relevant pages
 - Operating/Test Mode(s) (Mode(s)) on all the relevant pages
 - SECTION 1: Customer information
 - SECTION 2: Equipment under test (EUT) other than the Receipt Date
 - SECTION 4: Operation of EUT during testing
- * The laboratory is exempted from liability of any test results affected from the above information in SECTION 2 and 4.

SECTION 2: Equipment under test (EUT)

2.1 Identification of EUT

Type : Reader/Writer
Model Number : ICT-3404U-A
Serial Number : Refer to SECTION 4.2
Rating : DC 5 V
Receipt Date : June 29, 2020
Country of Mass-production : Japan
Condition : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification : No Modification by the test lab.

2.2 Product Description

Model: ICT-3404U-A (referred to as the EUT in this report) is a Reader/Writer.

Clock frequency(ies) in the system : USB 2.0 Full Speed: 12 MHz
Xtal: 16 MHz, 27.12 MHz
MCU Clock: 96 MHz

Radio Specification

Radio Type : Transceiver
Frequency of Operation : 13.56 MHz
Modulation : ASK
Antenna type : Loop

SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part 15 Subpart C
FCC Part 15 final revised on May 26, 2020 and effective July 27, 2020 except 15.258
Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators
Section 15.207 Conducted limits
Section 15.209 Radiated emission limits, general requirements
Section 15.215 Additional provisions to the general radiated emission limitations.
Section 15.225 Operation within the band 13.110 - 14.010 MHz.

* The revision does not affect the test result conducted before its effective date.
Also the EUT complies with FCC Part 15 Subpart B.

3.2 Procedures and results

Item	Test Procedure	Specification	Test method	Worst margin	Results	Remarks
Conducted Emission	FCC: ANSI C63.10:2013 6 Standard test methods ----- ISED: RSS-Gen 8.8	FCC: Section 15.207 ----- ISED: RSS-Gen 8.8	-	14.0 dB 0.25278 MHz QP, N	Complied a)	-
Electric Field Strength of Fundamental Emission	FCC: ANSI C63.10:2013 6 Standard test methods ----- ISED: RSS-Gen 6.4, 6.12	FCC: Section 15.225(a) ----- ISED: RSS-210 B.6	Radiated	46.8 dB Vertical Mode: NFC Communication	Complied b)	-
Electric Field Strength of Spurious Emission (within the 13.110-14.010 MHz band)	FCC: ANSI C63.10:2013 6 Standard test methods ----- ISED: RSS-Gen 6.4, 6.13	FCC: Section 15.225(b)(c) ----- ISED: RSS-210 B.6	Radiated	23.1 dB 13.349 MHz Vertical Mode: Transmitting 13.56 MHz	Complied b)	-
Electric Field Strength of Spurious Emission (outside of the 13.110-14.010 MHz band)	FCC: ANSI C63.10:2013 6 Standard test methods ----- ISED: RSS-Gen 6.4, 6.13	FCC: Section 15.209, Section 15.225 (d) ----- ISED: RSS-210 B.6	Radiated	2.2 dB 40.681 MHz Vertical	Complied# c)	-
20 dB Bandwidth	FCC: ANSI C63.10:2013 6 Standard test methods ----- ISED: -	FCC: Section 15.215(e) ----- ISED: -	Radiated	See data	Complied d)	-
Frequency Tolerance	FCC: ANSI C63.10:2013 6 Standard test methods ----- ISED: RSS-Gen 6.11, 8.11	FCC: Section 15.225(e) ----- ISED: RSS-210 B.6	Radiated	See data	Complied e)	-
Note: UL Japan, Inc.'s EMI Work Procedures No. 13-EM-W0420 and 13-EM-W0422						
a) Refer to APPENDIX 1 (data of Conducted Emission) b) Refer to APPENDIX 1 (data of Electric field strength of Fundamental emission and Spurious emission) c) Refer to APPENDIX 1 (data of Radiated emission) d) Refer to APPENDIX 1 (data of -20 dB Bandwidth and 99% Occupied Bandwidth) e) Refer to APPENDIX 1 (data of Frequency Tolerance)						
Symbols: Complied The data of this test item has enough margin, more than the measurement uncertainty. Complied# The data of this test item meets the limits unless the measurement uncertainty is taken into consideration.						

FCC Part 15.31 (e)

The RF Module has its own regulator.

The RF Module is constantly provided voltage through the regulator regardless of input voltage. Therefore, this EUT complies with the requirement.

FCC Part 15.203/212 Antenna requirement

The antenna is not removable from the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

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3.3 Addition to standard

Item	Test Procedure	Specification	Test method	Worst margin	Results	Remarks
99 % Occupied Bandwidth	ISED: RSS-Gen 6.7	-	Radiated	-	- d)	-

Note: UL Japan, Inc.'s EMI Work Procedures No. 13-EM-W0420 and 13-EM-W0422.

d) Refer to APPENDIX 1 (data of -20 dB Bandwidth and 99% Occupied Bandwidth)

* Other than above, no addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

There is no applicable rule of uncertainty in this applied standard. Therefore, the results are derived depending on whether or not laboratory uncertainty is applied.

The following uncertainties have been calculated to provide a confidence level of 95 % using a coverage factor $k=2$.
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Item	Frequency range	Uncertainty (+/-)			
		No. 1 SAC / SR	No. 2 SAC / SR	No. 3 SAC / SR	No. 4,5,6,8 SR
Conducted emission (AC Mains) LISN	150 kHz-30 MHz	2.6 dB	2.6 dB	2.5 dB	2.6 dB
Radiated emission (Measurement distance: 3 m)	9 kHz-30 MHz	3.0 dB	3.0 dB	3.0 dB	-
	30 MHz-200 MHz	4.6 dB	4.6 dB	4.6 dB	-
	200 MHz-1 GHz	6.0 dB	6.0 dB	6.0 dB	-
	1 GHz-6 GHz	4.9 dB	4.9 dB	4.9 dB	-
	6 GHz-18 GHz	5.5 dB	5.5 dB	5.5 dB	-

SAC=Semi-Anechoic Chamber

SR= Shielded Room is applied besides radiated emission

Antenna terminal test	Uncertainty (+/-)
Power Measurement above 1 GHz (Average Detector)_SPM-06	0.98 dB
Power Measurement above 1 GHz (Peak Detector)_SPM-06	1.75 dB
Power Measurement above 1 GHz (Average Detector)_SPM-07	0.89 dB
Power Measurement above 1 GHz (Peak Detector)_SPM-07	1.12 dB
Power Measurement above 1 GHz (Average Detector)_SPM-13	1.06 dB
Power Measurement above 1 GHz (Peak Detector)_SPM-13	1.24 dB
Spurious emission (Conducted) below 1GHz	0.9 dB
Spurious emission (Conducted) 1 GHz-3 GHz	0.9 dB
Spurious emission (Conducted) 3 GHz-18 GHz	2.9 dB
Spurious emission (Conducted) 18 GHz-26.5 GHz	2.6 dB
Spurious emission (Conducted) 26.5 GHz-40 GHz	2.0 dB
Bandwidth Measurement	0.07 %
Duty cycle and Time Measurement	0.262 %
Temperature	0.95 deg.C.
Voltage	0.83 %

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3.5 Test Location

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A2LA Certificate Number: 1266.03 (FCC Test Firm Registration Number: 626366, ISED Lab Company Number: 2973D)

Test site	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Maximum measurement distance
No.1 Semi-anechoic chamber	20.6 x 11.3 x 7.65	20.6 x 11.3	10 m
No.2 Semi-anechoic chamber	20.6 x 11.3 x 7.65	20.6 x 11.3	10 m
No.3 Semi-anechoic chamber	12.7 x 7.7 x 5.35	12.7 x 7.7	5 m
No.4 Semi-anechoic chamber	8.1 x 5.1 x 3.55	8.1 x 5.1	-
No.1 Shielded room	6.8 x 4.1 x 2.7	6.8 x 4.1	-
No.2 Shielded room	6.8 x 4.1 x 2.7	6.8 x 4.1	-
No.3 Shielded room	6.3 x 4.7 x 2.7	6.3 x 4.7	-
No.4 Shielded room	4.4 x 4.7 x 2.7	4.4 x 4.7	-
No.5 Shielded room	7.8 x 6.4 x 2.7	7.8 x 6.4	-
No.6 Shielded room	7.8 x 6.4 x 2.7	7.8 x 6.4	-
No.8 shielded room	3.45 x 5.5 x 2.4	3.45 x 5.5	-
No.1 Measurement room	2.55 x 4.1 x 2.5	-	-

3.6 Test data, Test instruments, and Test set up

Refer to APPENDIX.

SECTION 4: Operation of E.U.T. during testing

4.1 Operating Mode(s)

The EUT exercise program used during testing was designed to exercise the various system components in a manner similar to typical use.

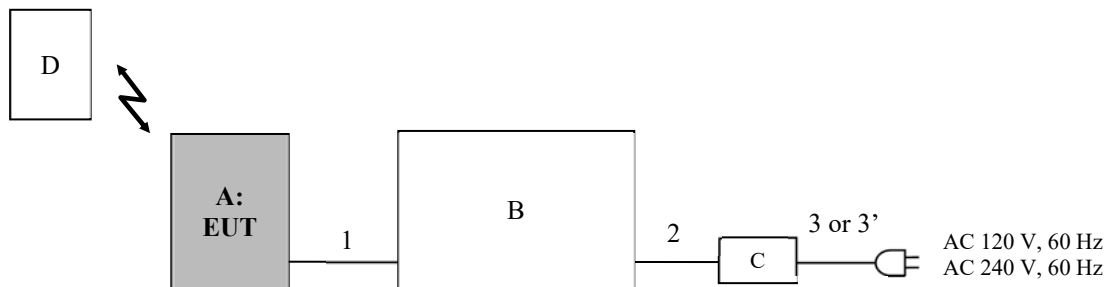
Test item	Operating mode	Tested frequency
All items except for Frequency tolerance	NFC Communication	13.56 MHz
	NFC Transmitting	13.56 MHz
Frequency tolerance	NFC Communication (Unmodulated)	13.56 MHz

Software: ICT-3404 Mod Test Version 1.0.2.2 (Date: 2020.7.1, Storage location: Driven by connected PC)
Power setting: Fixed

The carrier level and noise levels were confirmed with and without Tag, and the test was made with the condition that has the maximum noise.

Radiated emission (Carrier)	Radiated emission (Below 30 MHz)	Radiated emission (Above 30 MHz)
Without Tag	Without Tag	With Tag

4.2 Configuration and peripherals



* Cabling and setup(s) were taken into consideration and test data was taken under worse case conditions.
As a result of comparing AC 120 V and AC 240 V at pre-check, conducted emission test was performed with AC 120 V of the worst voltage as representative.

Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Reader/Writer	ICT-3404U-A	TE2006B029 TE2006B031 *1)	FUJIFILM Imaging Systems	EUT
B	Laptop PC	PCG-5Q2N	VBN-G3AANS	Sony Corporation	-
C	AC Adapter	VGP-AC16V11	0907G	Sony Corporation	-
D	Type A Tag	-	A01	FUJIFILM Imaging Systems	-

*1) Used for Conducted emission test (Antenna terminated)

List of cables used

No.	Name	Length (m)	Shield- Cable	Shield- Connector	Remarks
1	USB	1.0	Shielded	Shielded	-
2	DC	1.8	Unshielded	Unshielded	-
3'	AC	0.8	Unshielded	Unshielded	*2)
3'	AC	1.8	Unshielded	Unshielded	*3)

*2) Used for expect for Conducted emission test

*3) Used for Conducted emission test

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SECTION 5: Conducted emission

Test configuration and procedure

EUT was placed on a platform of nominal size, 1.0 m by 1.5 m, raised 0.8 m above the conducting ground plane. The table is made of expanded polystyrol and expanded polypropylene and the table top is covered with polycarbonate. That has very low permittivity.

The rear of tabletop was located 40 cm to the vertical conducting plane. The rear of EUT, including peripherals aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80 cm from any other grounded conducting surface. EUT was located 80 cm from a Line Impedance Stabilization Network (LISN) / Artificial mains Network (AMN) and excess AC cable was bundled in center.

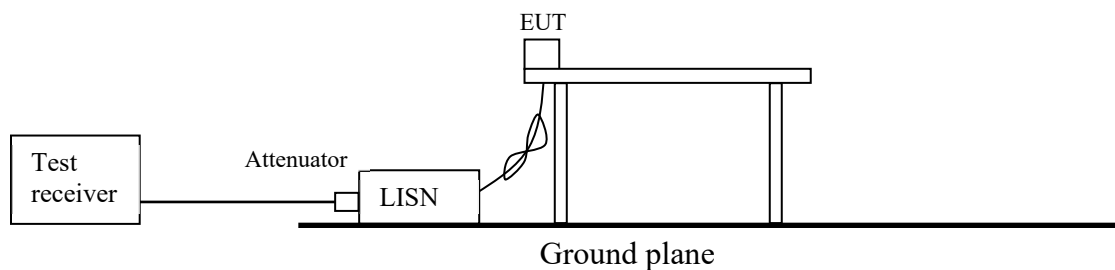
Each EUT current-carrying power lead, except the ground (safety) lead, was individually connected through a LISN / AMN to the input power source.

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT in a Shielded room. The EUT was connected to a LISN (AMN) via Laptop PC. An overview sweep with peak detection has been performed.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

Detector : QP and CISPR AV
Measurement range : 0.15 MHz - 30 MHz
Test data : APPENDIX
Test result : Pass

Figure 1: Test Setup



SECTION 6: 20 dB bandwidth & 99 % Occupied bandwidth

Test procedure

The test was measured with a spectrum analyzer using a test fixture.

Test	Span	RBW	VBW	Sweep	Detector	Trace	Instrument used
20 dB Bandwidth	100 kHz	1 kHz	3 kHz	Auto	Peak	Max Hold	Spectrum Analyzer
99 % Occupied Bandwidth (OBW)	Enough width to display	1 to 5 % of OBW	Three times of RBW	Auto	Peak *1)	Max Hold *1)	Spectrum Analyzer

*1) The measurement was performed with Peak detector, Max Hold since the duty cycle was not 100%.

Test data : APPENDIX
Test result : Pass

SECTION 7: Frequency tolerance

Test procedure

The test was measured with a spectrum analyzer (with marker frequency counter function) using a test fixture.
The temperature test was started after the temperature stabilization time of 30 minutes.
The test was begun from 50 deg.C and the temperature was lowered each 10 deg.C.

Test data : APPENDIX
Test result : Pass

SECTION 8: Radiated emission

Test configuration and procedure

EUT was placed on a platform of nominal size, 1.0 m by 1.5 m, raised 0.8 m above the conducting ground plane. The table is made of expanded polystyrol and expanded polypropylene and the table top is covered with polycarbonate. That has very low permittivity.

The rear of EUT, including its peripherals was aligned and flushed with rear of tabletop.

Photographs of the set up are shown in APPENDIX 3.

The Radiated Electric Field Strength intensity has been measured on a semi-anechoic chamber with a ground plane at a distance of 3 m.

Although these tests were performed other than open area test site, adequate comparison measurements were confirmed against 30 m open are test site. Therefore sufficient tests were made to demonstrate that the alternative site produces results that correlate with the ones of tests made in an open field based on KDB 414788.

These tests were performed in semi anechoic chamber. Therefore the measured level of emissions may be higher than if measurements were made without a ground plane.

However test results were confirmed to pass against standard limit.

The Radiated Electric Field Strength intensity has been measured with a ground plane and at a distance of 3 m.

Frequency: From 9 kHz to 30 MHz at distance 3 m (Refer to Figure 3)

The EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for vertical polarization (antenna angle: 0 deg., 45 deg., 90 deg. and 135 deg.) and horizontal polarization. Drawing of the antenna direction is shown in Figure 2.

Frequency: From 30 MHz to 1 GHz at distance 3 m (Refer to Figure 3).

The measuring antenna height was varied between 1 m and 4 m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization.

Measurements were performed with QP, PK, and AV detector.

The radiated emission measurements were made with the following detector function of the test receiver.

	9 kHz to 90 kHz & 110 kHz to 150 kHz	90 kHz to 110 kHz	150 kHz to 490 kHz	490 kHz to 30 MHz	30 MHz to 1 GHz
Detector Type	PK/AV	QP	PK/AV	QP	QP
IF Bandwidth	200 Hz	200 Hz	10 kHz	9 kHz	120 kHz
Distance factor *1)	-80 dB	-80 dB	-80 dB	-40 dB	-
Measuring antenna	Loop antenna				Biconical (30 MHz - 199.999 MHz) Logperiodic (200 MHz - 1 GHz)

*1) FCC 15.31 (f)(2) (9 kHz-30 MHz)

Distance Factor: $40 \times \log(3 \text{ m} / 300 \text{ m}) = -80 \text{ dB}$

Distance Factor: $40 \times \log(3 \text{ m} / 30 \text{ m}) = -40 \text{ dB}$

The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

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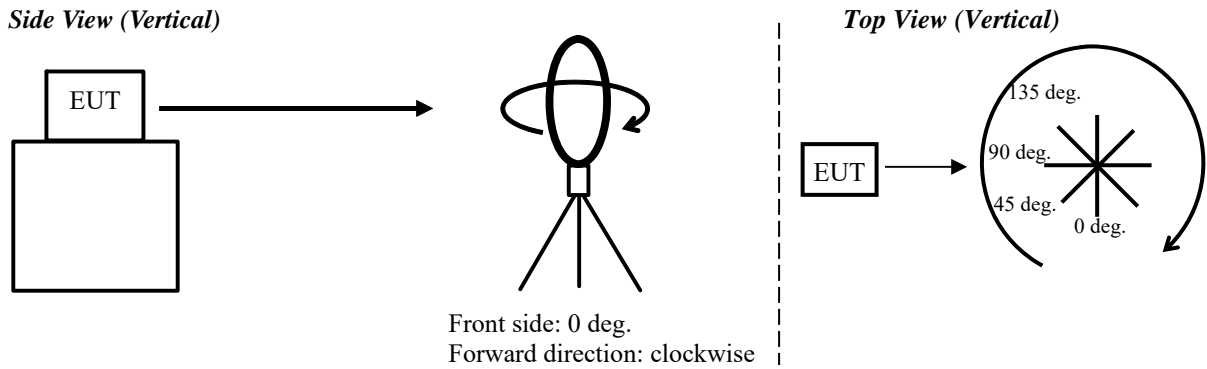
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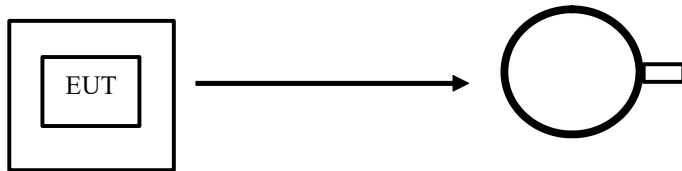
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Figure 2. Direction of the Loop Antenna



Top View (Horizontal)



Antenna was not rotated.

Figure 3. Antenna angle

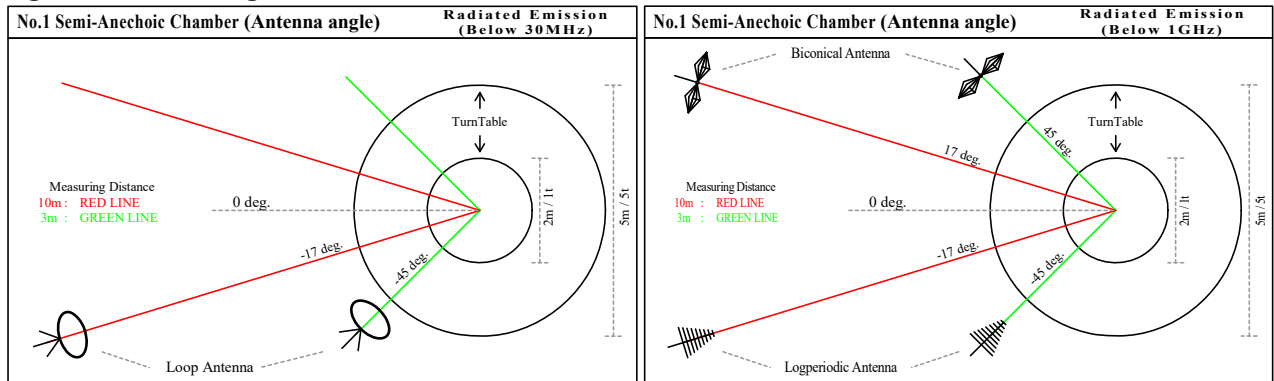
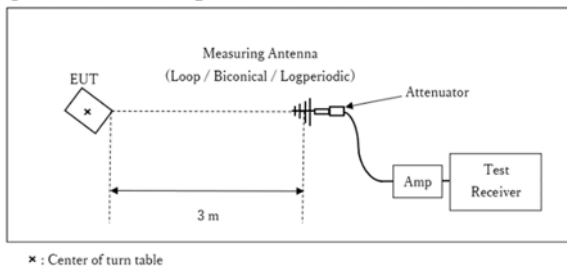


Figure 4. Test setup



Measurement range : 9 kHz - 1 GHz
 Test data : APPENDIX
 Test result : Pass

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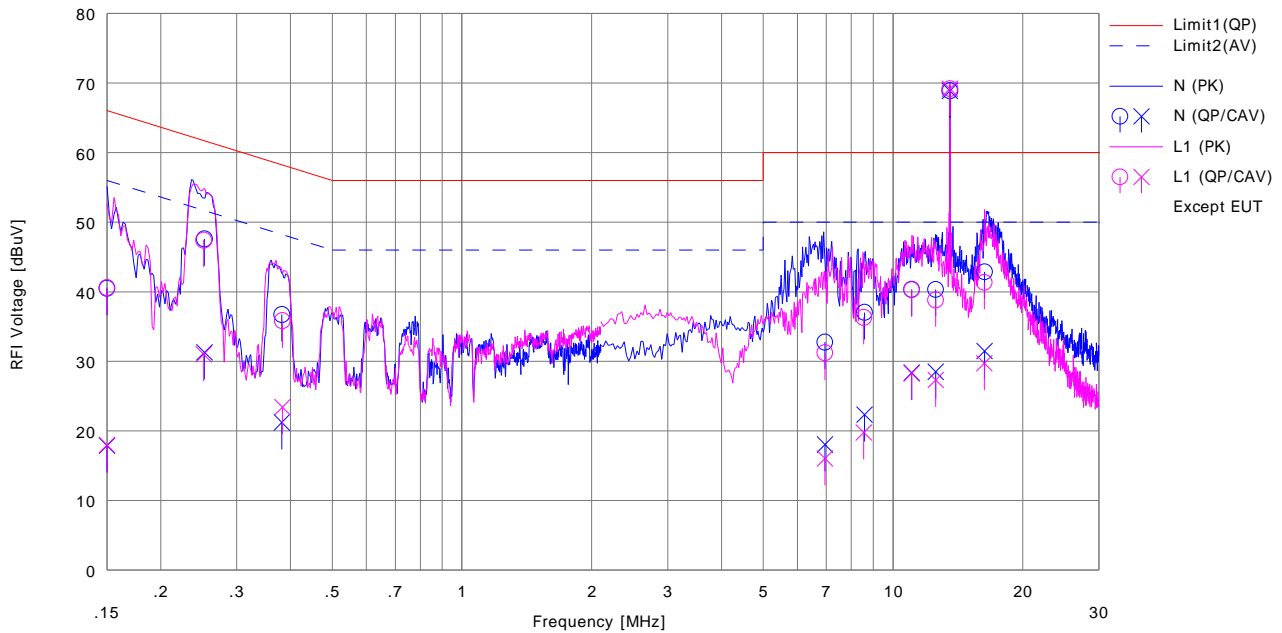
DATA OF CONDUCTED EMISSION TEST

UL Japan, Inc. Shonan EMC Lab. No.1 Shielded Room
Date : 2020/07/02

Company : FUJIFILM Corporation	Mode : NFC Communication
Kind of EUT : Reader/Writer	Order No. : 13382555S
Model No. : ICT-3404U-A	Power : AC 120 V / 60 Hz
Serial No. : TE2006B029	Temp./Humi. : 24 deg.C / 54 %RH
Remarks : with Tag, Refer to the data on the next page for the carrier frequency (13.56 MHz)	

Limit : FCC_Part 15 Subpart C(15.207)

Engineer : Takahiro Kawakami



No.	Freq. [MHz]	Reading		C.Fac [dB]	Results		Limit		Margin		Phase	Comment
		<QP>	<CAV>		<QP>	<CAV>	<QP>	<AV>	<QP>	<AV>		
		[dBuV]	[dBuV]		[dBuV]	[dBuV]	[dBuV]	[dBuV]	[dB]	[dB]		
1	0.15000	28.00	5.40	12.48	40.48	17.88	66.00	56.00	25.5	38.1	N	
2	0.25278	35.10	18.80	12.49	47.59	31.29	61.67	51.67	14.0	20.3	N	
3	0.38208	24.20	8.70	12.51	36.71	21.21	58.23	48.23	21.5	27.0	N	
4	6.94560	19.80	5.10	12.95	32.75	18.05	60.00	50.00	27.2	31.9	N	
5	8.59063	24.00	9.30	13.03	37.03	22.33	60.00	50.00	22.9	27.6	N	
6	11.05308	27.20	15.20	13.15	40.35	28.35	60.00	50.00	19.6	21.6	N	
7	12.55670	27.10	15.30	13.21	40.31	28.51	60.00	50.00	19.6	21.4	N	
8	13.56000	55.60	55.60	13.26	68.86	68.86	60.00	50.00	-8.9	-18.9	N	Reference
9	16.30815	29.50	18.10	13.37	42.87	31.47	60.00	50.00	17.1	18.5	N	
10	0.15000	28.10	5.50	12.49	40.59	17.99	66.00	56.00	25.4	38.0	L1	
11	0.25190	34.90	18.50	12.50	47.40	31.00	61.69	51.69	14.2	20.6	L1	
12	0.38287	23.30	10.90	12.52	35.82	23.42	58.22	48.22	22.4	24.8	L1	
13	6.94700	18.30	3.10	12.92	31.22	16.02	60.00	50.00	28.7	33.9	L1	
14	8.55300	23.30	6.80	12.98	36.28	19.78	60.00	50.00	23.7	30.2	L1	
15	11.05422	27.20	15.20	13.08	40.28	28.28	60.00	50.00	19.7	21.7	L1	
16	12.55390	25.70	14.20	13.12	38.82	27.32	60.00	50.00	21.1	22.6	L1	
17	13.56000	56.00	56.00	13.16	69.16	69.16	60.00	50.00	-9.2	-19.2	L1	Reference
18	16.29180	28.10	16.50	13.23	41.33	29.73	60.00	50.00	18.6	20.2	L1	

Calculation: Result [dBuV] = Reading [dBuV] + C.Fac (LISN (AMN) + Cable + ATT) [dB]
LISN (AMN) = SLS-02

DATA OF CONDUCTED EMISSION TEST

UL Japan, Inc. Shonan EMC Lab. No.1 Shielded Room
Date : 2020/07/02

Company : FUJIFILM Corporation
 Kind of EUT : Reader/Writer
 Model No. : ICT-3404U-A
 Serial No. : TE2006B031
 Remarks : Antenna:terminated

Mode : NFC Communication
 Order No. : 13382555S
 Power : AC 120 V / 60 Hz (USB DC 5.0 V)
 Temp./Humi. : 24 deg.C / 54 %RH

Limit : FCC_Part 15 Subpart C(15.207)

Engineer : Takahiro Kawakami

<< QP/CAV DATA >>

No.	Freq. [MHz]	Reading		C.Fac [dB]	Results		Limit		Margin		Phase	Comment
		<QP>	<CAV>		<QP>	<CAV>	<QP>	<AV>	<QP>	<AV>		
		[dBuV]	[dBuV]		[dBuV]	[dBuV]	[dBuV]	[dBuV]	[dB]	[dB]		
1	13.56000	26.30	15.20	13.26	39.56	28.46	60.00	50.00	20.4	21.5	N	
2	13.56000	23.80	13.10	13.16	36.96	26.26	60.00	50.00	23.0	23.7	L1	

Calculation: Result[dBuV]=Reading[dBuV]+C.Fac(LISN(AMN)+Cable+ATT)[dB]
 LISN(AMN)=SLS-02

Data of Electric field strength of Fundamental emission and Spurious emission within the band: FCC15.225(a)(b)(c)

UL Japan, Inc.
Shonan EMC Lab., No.1 Semi Anechoic Chamber

Company: FUJIFILM Corporation
Equipment: Reader/writer
Model: ICT-3404U-A
Sample No.: TE2006B029
Power: DC 5.0 V (USB)
Mode: NFC Communication

Regulation: FCC Part15 Subpart C 15.225
Test Distance: 3m
Date: July 1, 2020
Temperature: 23 deg.C
Humidity: 60 %RH
ENGINEER: Takahiro Kawakami

Remarks: : without Tag, EUT Axis:Hor_Y / Ver_Y , Vertical polarization (antenna angle) of the worst case: 0deg

Fundamental emission

No.	FREQ [MHz]	Test Receiver Reading		Antenna Factor [dB/m]	Loss [dB]	AMP GAIN [dB]	Distance factor [dB]	RESULT		LIMIT (30m) [dBuV/m]	MARGIN	
		Hor [dBuV]	Ver [dBuV]					Hor [dBuV/m]	Ver [dBuV/m]		Hor [dB]	Ver [dB]
1	13.560	70.5	82.9	19.5	6.6	31.9	-40.0	24.7	37.1	83.9	59.2	46.8

Calculation:Result[dBuV/m]=Reading[dBuV]+Ant.Fac[dB/m]+Loss(Cable+ATT)[dB]-Gain(AMP)[dB]+Distance factor[dB]

Distance factor: 40 x log (3m/30m) = -40 dB

Limits (30m)

•13.553MHz to 13.567MHz : 83.9dBuV/m (FCC 15.225(a))

Spurious emission within the band

No.	FREQ [MHz]	Test Receiver Reading		Antenna Factor [dB/m]	Loss [dB]	AMP GAIN [dB]	Distance factor [dB]	RESULT		LIMIT (30m) [dBuV/m]	MARGIN	
		Hor [dBuV]	Ver [dBuV]					Hor [dBuV/m]	Ver [dBuV/m]		Hor [dB]	Ver [dB]
1	13.110	29.7	29.7	19.5	6.6	31.9	-40.0	-16.1	-16.1	29.5	45.6	45.6
2	13.410	30.6	37.2	19.5	6.6	31.9	-40.0	-15.2	-8.6	40.5	55.7	49.1
3	13.553	55.3	68.5	19.5	6.6	31.9	-40.0	9.5	22.7	50.4	40.9	27.7
4	13.567	55.6	68.6	19.5	6.6	31.9	-40.0	9.8	22.8	50.4	40.6	27.6
5	13.710	30.4	36.9	19.5	6.6	31.9	-40.0	-15.4	-8.9	40.5	55.9	49.4
6	14.010	29.8	29.6	19.6	6.6	31.9	-40.0	-15.9	-16.1	29.5	45.4	45.6

Calculation:Result[dBuV/m]=Reading[dBuV]+Ant.Fac[dB/m]+Loss(Cable+ATT)[dB]-Gain(AMP)[dB]+Distance factor[dB]

Outside filed strength frequencies

•Fc±7kHz:13.553MHz to 13.567MHz

•Fc±150kHz:13.410MHz to 13.710MHz

•Fc±450kHz:13.110MHz to 14.010MHz

Fc = 13.56MHz

Limits (30m)

•13.410MHz to 13.553MHz and 13.567MHz to 13.710MHz : 50.4dBuV/m (FCC 15.225(b))

•13.110MHz to 13.410MHz and 13.710MHz to 14.010MHz : 40.5dBuV/m (FCC 15.225(c))

•Below 13.110MHz and Above 14.010MHz : 29.5dBuV/m (FCC 15.225(d)and FCC 15.209)

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Data of Electric field strength of Fundamental emission and Spurious emission within the band: FCC15.225(a)(b)(c)

UL Japan, Inc.
Shonan EMC Lab., No.1 Semi Anechoic Chamber

Company: FUJIFILM Corporation
Equipment: Reader/writer
Model: ICT-3404U-A
Sample No.: TE2006B029
Power: DC 5.0 V (USB)
Mode: Transmitting 13.56MHz

Regulation: FCC Part15 Subpart C 15.225
Test Distance: 3m
Date: July 1, 2020
Temperature: 23 deg.C
Humidity: 60 %RH
ENGINEER: Takahiro Kawakami

Remarks: : EUT Axis:Hor_Y / Ver_Y , Vertical polarization (antenna angle) of the worst case: 0deg

Fundamental emission

No.	FREQ [MHz]	Test Receiver Reading		Antenna Factor [dB/m]	Loss [dB]	AMP GAIN [dB]	Distance factor [dB]	RESULT		LIMIT (30m) [dBuV/m]	MARGIN	
		Hor [dBuV]	Ver [dBuV]					Hor [dBuV/m]	Ver [dBuV/m]		Hor [dB]	Ver [dB]
1	13.560	69.3	81.8	19.5	6.6	31.9	-40.0	23.5	36.0	83.9	60.4	47.9

Calculation:Result[dBuV/m]=Reading[dBuV]+Ant.Fac[dB/m]+Loss(Cable+ATT)[dB]-Gain(AMP)[dB]+Distance factor[dB]

Distance factor: $40 \times \log(3\text{m}/30\text{m}) = -40 \text{ dB}$

Limits (30m)

•13.553MHz to 13.567MHz : 83.9dBuV/m (FCC 15.225(a))

Spurious emission within the band

No.	FREQ [MHz]	Test Receiver Reading		Antenna Factor [dB/m]	Loss [dB]	AMP GAIN [dB]	Distance factor [dB]	RESULT		LIMIT (30m) [dBuV/m]	MARGIN	
		Hor [dBuV]	Ver [dBuV]					Hor [dBuV/m]	Ver [dBuV/m]		Hor [dB]	Ver [dB]
1	13.032	36.4	46.3	19.5	6.6	31.9	-40.0	-9.4	0.5	29.5	38.9	29.0
2	13.110	30.0	32.2	19.5	6.6	31.9	-40.0	-15.8	-13.6	29.5	45.3	43.1
3	13.349	51.4	63.2	19.5	6.6	31.9	-40.0	5.6	17.4	40.5	34.9	23.1
4	13.410	45.9	57.7	19.5	6.6	31.9	-40.0	0.1	11.9	40.5	40.4	28.6
5	13.553	55.6	67.4	19.5	6.6	31.9	-40.0	9.8	21.6	50.4	40.6	28.8
6	13.567	55.9	67.6	19.5	6.6	31.9	-40.0	10.1	21.8	50.4	40.3	28.6
7	13.710	45.5	57.3	19.5	6.6	31.9	-40.0	-0.3	11.5	40.5	40.8	29.0
8	13.772	51.6	63.1	19.5	6.6	31.9	-40.0	5.8	17.3	40.5	34.7	23.2
9	14.010	29.8	30.7	19.6	6.6	31.9	-40.0	-15.9	-15	29.5	45.4	44.5
10	14.197	36.5	45.0	19.6	6.6	31.9	-40.0	-9.2	-0.7	29.5	38.7	30.2

Calculation:Result[dBuV/m]=Reading[dBuV]+Ant.Fac[dB/m]+Loss(Cable+ATT)[dB]-Gain(AMP)[dB]+Distance factor[dB]

Outside filed strength frequencies

- Fc±7kHz:13.553MHz to 13.567MHz
 - Fc±150kHz:13.410MHz to 13.710MHz
 - Fc±450kHz:13.110MHz to 14.010MHz
- Fc = 13.56MHz

Limits (30m)

- 13.410MHz to 13.553MHz and 13.567MHz to 13.710MHz : 50.4dBuV/m (FCC 15.225(b))
- 13.110MHz to 13.410MHz and 13.710MHz to 14.010MHz : 40.5dBuV/m (FCC 15.225(c))
- Below 13.110MHz and Above 14.010MHz : 29.5dBuV/m (FCC 15.225(d)and FCC 15.209)

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Radiated Emission

UL Japan, Inc.
Shonan EMC Lab. No.1 Semi Anechoic Chamber

Company: FUJIFILM Corporation
Equipment: Reader/writer
Model: ICT-3404U-A TE2006B029
Sample No.: DC 5.0 V (USB)
Power: NFC Communication
Mode:

Regulation: FCC Part15 Subpart C 15.225
Test Distance: 3m
Date: July 1, 2020
Temperature: 23 deg.C
Humidity: 60 %RH
ENGINEER: Takahiro Kawakami

EUT axis: Below 30MHz(Horizontal Y-axis, Vertical Y-axis), without Tag, Vertical polarization(antenna angle)of the worst case: 0 deg)
Above 30MHz(Horizontal: Z-axis, Vertical: Y-axis), with Tag

Remarks:

Polarity	Frequency [MHz]	Detector	Reading [dBuV]	Ant.Fac. [dB/m]	Loss [dB]	Gain [dB]	Distance Factor [dB]	Result [dBuV/m]	Limit [dBuV/m]	Margin [dB]	Height [cm]	Angle [deg.]	Remark
Hori.	27.120	QP	28.5	20.1	6.9	31.8	-40.0	-16.3	29.5	45.8	-	183	* Limit: 30m
Hori.	54.003	QP	43.0	9.8	7.4	31.8	0.0	28.4	40.0	11.6	357	234	
Hori.	67.800	QP	44.5	6.8	7.4	31.8	0.0	26.9	40.0	13.1	288	17	
Hori.	70.194	QP	43.8	6.5	7.6	31.8	0.0	26.1	40.0	13.9	270	33	
Hori.	72.002	QP	45.8	6.4	7.7	31.8	0.0	28.1	40.0	11.9	264	15	
Hori.	162.720	QP	39.3	15.3	8.9	31.8	0.0	31.7	43.5	11.8	212	23	
Hori.	786.480	QP	38.3	20.6	9.1	32.0	0.0	36.0	46.0	10.0	139	66	
Vert.	27.120	QP	29.8	20.1	6.9	31.8	-40.0	-15.0	29.5	44.5	-	134	* Limit: 30m
Vert.	40.681	QP	47.7	14.6	7.3	31.8	0.0	37.8	40.0	2.2	100	313	
Vert.	53.998	QP	47.1	9.8	7.4	31.8	0.0	32.5	40.0	7.5	100	139	
Vert.	67.797	QP	54.4	6.8	7.4	31.8	0.0	36.8	40.0	3.2	100	123	
Vert.	813.600	QP	37.9	20.9	9.3	32.0	0.0	36.1	46.0	9.9	100	220	

Result = Reading + Ant Factor + Loss (Cable+ATT+ΔAF(above 30MHz)) - Gain(Ampriifier) + Distance factor(below 30MHz)

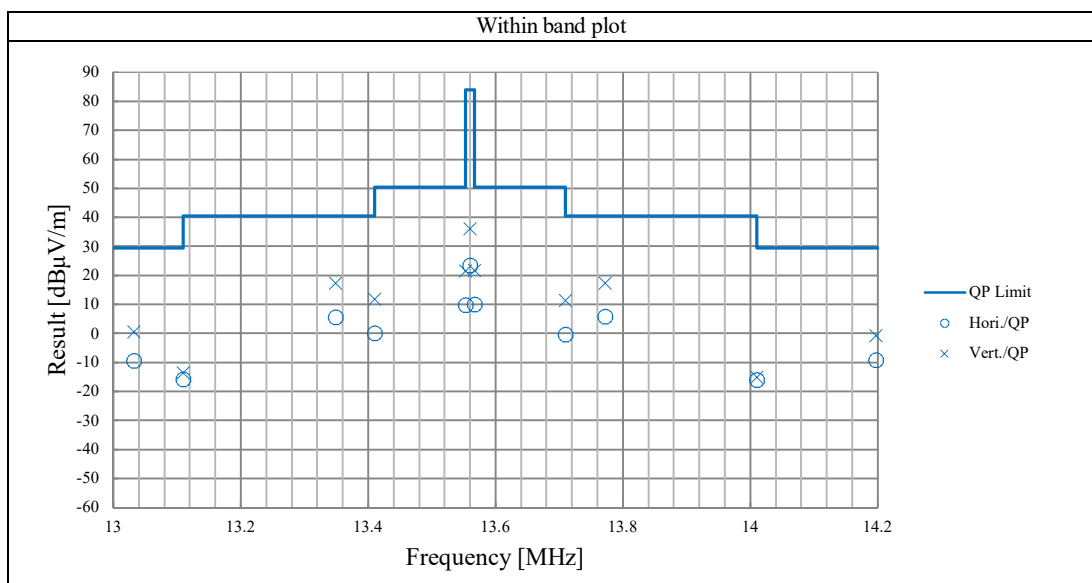
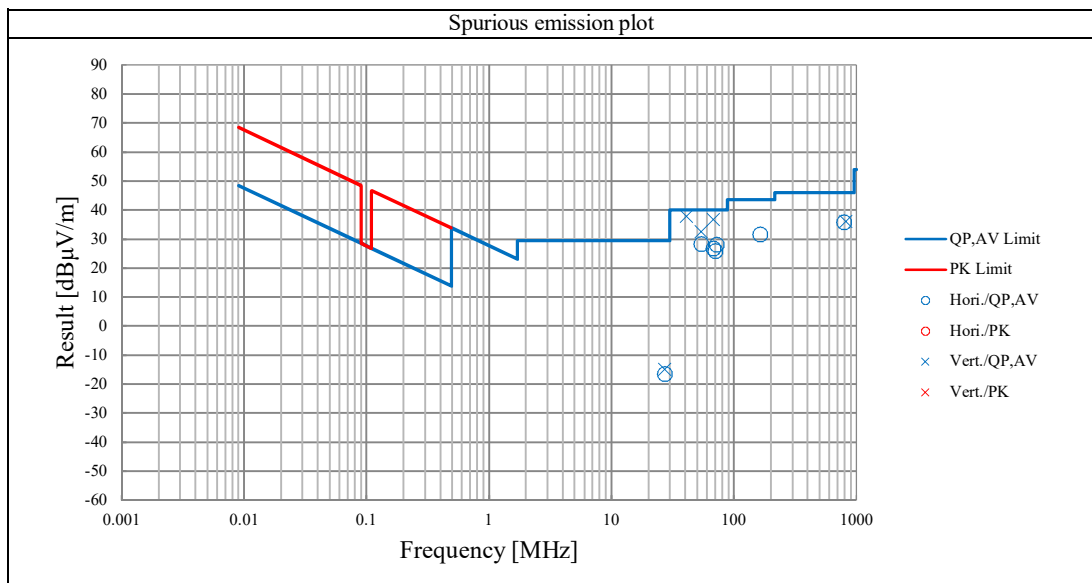
* Other frequency noises omitted in this report were not seen or have enough margin (more than 20dB).

* Carrier level (Result at 3m): Hor= 64.7dBuV/m, Ver= 77.1 dBuV/m

Radiated Emission (Worst mode plot)

UL Japan, Inc.
Shonan EMC Lab. No.1 Semi Anechoic Chamber

Company:	FUJIFILM Corporation	Regulation:	FCC Part15 Subpart C 15.225
Equipment:	Reader/writer	Test Distance:	3m
Model:	ICT-3404U-A	Date:	July 1, 2020
Sample No.:	TE2006B029	Temperature:	23 deg.C
Power:	DC 5.0 V (USB)	Humidity:	60 %RH
Mode:	NFC Communication(Spurious emission plot) Transmitting 13.56 MHz (Within band plot)	ENGINEER:	Takahiro Kawakami
EUT axis:	Below 30MHz(Horizontal Y-axis, Vertical Y-axis), without Tag, Vertical polarization(antenna angle)of the worst case: 0 deg) Above 30MHz(Horizontal: Z-axis, Vertical: Y-axis), with Tag		
Remarks:	These plots data contains sufficient number to show the trend of characteristic features for EUT.		



Data of Frequency Tolerance

UL Japan, Inc.

Shonan EMC Lab. No.5 Shielded room

Company FUJIFILM Corporation
 Equipment Reader/writer
 Model ICT-3404U-A
 Serial No. TE2006B029
 Power DC 5V
 Mode Transmitting 13.56 MHz

Regulation FCC Part15 Subpart C 15.225 (e)
 Date Jul 10, 2020
 Temperature 25 deg.C
 Humidity 53 %RH
 ENGINEER Makoto Hosaka

Temperature Variation: -20deg.C

Test Conditions	Original Frequency (MHz)	Measure Frequency (MHz)	Frequency Error (MHz)	Frequency tolerance (%)	Limit (%)
startup	13.56	13.560073	0.000073	0.00054	0.010
after 2minutes	13.56	13.560110	0.000110	0.00081	0.010
after 5minutes	13.56	13.560113	0.000113	0.00083	0.010
after 10minutes	13.56	13.560112	0.000112	0.00083	0.010

Temperature Variation: -10deg.C

Test Conditions	Original Frequency (MHz)	Measure Frequency (MHz)	Frequency Error (MHz)	Frequency tolerance (%)	Limit (%)
startup	13.56	13.560101	0.000101	0.00074	0.010
after 2minutes	13.56	13.560112	0.000112	0.00083	0.010
after 5minutes	13.56	13.560108	0.000108	0.00080	0.010
after 10minutes	13.56	13.560105	0.000105	0.00077	0.010

Temperature Variation: 0deg.C

Test Conditions	Original Frequency (MHz)	Measure Frequency (MHz)	Frequency Error (MHz)	Frequency tolerance (%)	Limit (%)
startup	13.56	13.560113	0.000113	0.00083	0.010
after 2minutes	13.56	13.560097	0.000097	0.00072	0.010
after 5minutes	13.56	13.560088	0.000088	0.00065	0.010
after 10minutes	13.56	13.560085	0.000085	0.00063	0.010

Temperature Variation: 10deg.C

Test Conditions	Original Frequency (MHz)	Measure Frequency (MHz)	Frequency Error (MHz)	Frequency tolerance (%)	Limit (%)
startup	13.56	13.560131	0.000131	0.00097	0.010
after 2minutes	13.56	13.560081	0.000081	0.00060	0.010
after 5minutes	13.56	13.560065	0.000065	0.00048	0.010
after 10minutes	13.56	13.560059	0.000059	0.00044	0.010

Temperature Variation: 20deg.C

Test Conditions	Original Frequency (MHz)	Measure Frequency (MHz)	Frequency Error (MHz)	Frequency tolerance (%)	Limit (%)
startup	13.56	13.560079	0.000079	0.00058	0.010
after 2minutes	13.56	13.560043	0.000043	0.00032	0.010
after 5minutes	13.56	13.560034	0.000034	0.00025	0.010
after 10minutes	13.56	13.560032	0.000032	0.00024	0.010

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Data of Frequency Tolerance

Temperature Variation: 30deg.C

Test Conditions	Original Frequency (MHz)	Measure Frequency (MHz)	Frequency Error (MHz)	Frequency tolerance (%)	Limit (%)
startup	13.56	13.560052	0.000052	0.00038	0.010
after 2minutes	13.56	13.560022	0.000022	0.00016	0.010
after 5minutes	13.56	13.560014	0.000014	0.00010	0.010
after 10minutes	13.56	13.560012	0.000012	0.00009	0.010

Temperature Variation: 40deg.C

Test Conditions	Original Frequency (MHz)	Measure Frequency (MHz)	Frequency Error (MHz)	Frequency tolerance (%)	Limit (%)
startup	13.56	13.560014	0.000014	0.00010	0.010
after 2minutes	13.56	13.560006	0.000006	0.00004	0.010
after 5minutes	13.56	13.560003	0.000003	0.00002	0.010
after 10minutes	13.56	13.560003	0.000003	0.00002	0.010

Temperature Variation: 50deg.C

Test Conditions	Original Frequency (MHz)	Measure Frequency (MHz)	Frequency Error (MHz)	Frequency tolerance (%)	Limit (%)
startup	13.56	13.560013	0.000013	0.00010	0.010
after 2minutes	13.56	13.560007	0.000007	0.00005	0.010
after 5minutes	13.56	13.560012	0.000012	0.00009	0.010
after 10minutes	13.56	13.560014	0.000014	0.00010	0.010

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Data of Frequency Tolerance

UL Japan, Inc.

Shonan EMC Lab. No.5 Shielded room

Company FUJIFILM Corporation
 Equipment Reader/writer
 Model ICT-3404U-A
 Serial No. TE2006B029
 Power DC 5V
 Mode Transmitting 13.56 MHz

Regulation FCC Part15 Subpart C 15.225 (e)
 Date Jul 10, 2020
 Temperature 25 deg.C
 Humidity 53 %RH
 ENGINEER Makoto Hosaka

Voltage Variation: DC 4.25 V**Temperature Variation: 20deg.C**

Test Conditions	Original Frequency (MHz)	Measure Frequency (MHz)	Frequency Error (MHz)	Frequency tolerance (%)	Limit (%)
startup	13.56	13.560073	0.000073	0.00054	0.010
after 2minutes	13.56	13.560052	0.000052	0.00038	0.010
after 5minutes	13.56	13.560047	0.000047	0.00035	0.010
after 10minutes	13.56	13.560047	0.000047	0.00035	0.010

Voltage Variation: DC 5.75 V**Temperature Variation: 20deg.C**

Test Conditions	Original Frequency (MHz)	Measure Frequency (MHz)	Frequency Error (MHz)	Frequency tolerance (%)	Limit (%)
startup	13.56	13.560069	0.000069	0.00051	0.010
after 2minutes	13.56	13.560038	0.000038	0.00028	0.010
after 5minutes	13.56	13.560029	0.000029	0.00021	0.010
after 10minutes	13.56	13.560027	0.000027	0.00020	0.010

UL Japan, Inc.**Shonan EMC Lab.**

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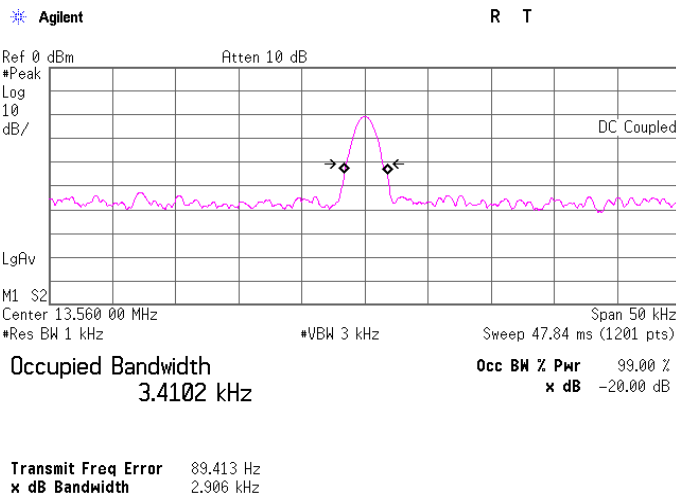
20dB bandwidth & 99% Occupied bandwidth: FCC 15.215 / RSS-Gen

UL Japan, Inc.
Shonan EMC Lab. No.5 Shielded Room

Company: FUJIFILM Corporation
 Equipment: Reader/writer
 Model: ICT-3404U-A
 Sample No.: TE2006B029
 Power: DC 5.0 V (USB)
 Mode: Transmitting 13.56MHz

Regulation: FCC Part15 Subpart C 15.215
 Date: Jul 10, 2020
 Temperature: 25 deg.C
 Humidity: 53 %RH
 ENGINEER: Makoto Hosaka

20dB Bandwidth: 2.906 kHz
99% Occupied Bandwidth: 3.410 kHz



*Since the transmitter signal is CW-like it is impractical to use a RBW setting of 1 – 5% of the emission bandwidth since the emission bandwidth will be proportional to the RBW.

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APPENDIX 2

Test Instruments

EMI test equipment

Test Name	Local ID	LIMS ID	Description	Manufacturer	Model	Serial	Last Calibration Date	Calibration Interval (Month)
CE	SAT3-13	150923	Attenuator	JFW	50HF-003N	-	2020/01/30	12
CE	SCC-A12/A13/SRSE-01	144966	Coaxial Cable&RF Selector	Suhner/Suhner/TOYO	RG223U/141PE/NS4906	-/0901-269(RF Selector)	2020/04/12	12
CE	SLS-02	145539	LISN	Rohde & Schwarz	ENV216	100512	2020/02/18	12
CE	SOS-16	167990	Humidity Indicator	CUSTOM	CTH-202	708Q08R	2019/12/19	12
CE,RE	COTS-SEMI-5	170932	EMI Software	TSJ (Techno Science Japan)	TEPTO-DV3(RE,CE,ME,PE)	-	-	-
CE,RE	KJM-09	145929	Measure	KOMELON	KMC-36	-	-	-
CE,RE	STR-01	145790	Test Receiver	Rohde & Schwarz	ESU40	100093	2020/04/24	12
CE,RE	STS-01	145792	Digital Hitester	Hioki	3805-50	80997812	2019/10/01	12
RE	KAT6-04	144899	Attenuator	Inmet	18N-6dB	-	2019/12/05	12
RE	SAEC-01(NSA)	145597	Semi-Anechoic Chamber	TDK	SAEC-01(NSA)	1	2020/04/08	12
RE	SAF-01	145003	Pre Amplifier	SONOMA	310N	290211	2020/02/19	12
RE	SAT3-09	144959	Attenuator	JFW	50HF-003N	-	2019/08/06	12
RE	SAT6-15	167096	Attenuator	JFW	50HF-006N	-	2020/02/21	12
RE	SBA-01	145161	Biconical Antenna	Schwarzbeck Mess - Elektronik	BBA9106	91032664	2020/04/04	12
RE	SCC-A1/A3/A5/A7/A8/A13/SRSE-01	144967	Coaxial Cable&RF Selector	Fujikura/Fujikura/Suhner/Suhner/Suhner/Suhner/TOYO	8D2W/12DSFA/141PE/141PE/141PE/NS4906	-/0901-269(RF Selector)	2020/04/12	12
RE	SCC-A2/A4/A6/A7/A8/A13/SRSE-01	144968	Coaxial Cable&RF Selector	Fujikura/Fujikura/Suhner/Suhner/Suhner/Suhner/TOYO	8D2W/12DSFA/141PE/141PE/141PE/NS4906	-/0901-269(RF Selector)	2020/04/12	12
RE	SCC-M1	194601	Coaxial Cable	Fujikura	5D-2W	-	2019/12/17	12
RE	SLA-05	145527	Logperiodic Antenna	Schwarzbeck Mess - Elektronik	VUSLP9111B	193	2020/04/04	12
RE	SLP-02	145536	Loop Antenna	Rohde & Schwarz	HFH2-Z2	100218	2020/04/15	12
RE	SOS-20	191837	Humidity Indicator	CUSTOM	CTH-201	-	2019/12/12	12
TF	KTS-07	145111	Digital Tester	SANWA	PC500	7019232	2019/10/01	12
TF	SCH-01	145200	Temperature and Humidity Chamber	ESPEC	PL-1KT	14020837	2020/04/02	12
TF	SFC-03	183119	Microwave Counter	Keysight Technologies Inc	53151A	US40511493	2019/11/06	12
TF	SOS-19	175823	Humidity Indicator	CUSTOM	CTH-201	-	2019/12/19	12
TF	SRENT-15	160899	Spectrum Analyzer	Keysight Technologies Inc	E4440A	MY46185516	2020/01/15	12
TF	SSCA-01	146178	Search coil	Langer	RF-R 400-1	02-0634	-	-

*Hyphens for Last Calibration Date and Cal Int (month) are instruments that Calibration is not required (e.g. software), or instruments checked in advance before use.

The expiration date of the calibration is the end of the expired month.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards

Test Item:

CE: Conducted emission,

RE: Radiated emission,

TF: Test fixture